

Notice of References Cited

Application/Control No.

10/582,616

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

George Fourson

Art Unit

2823

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-5,314,831 A | 05-1994 | Hirae et al. | 356/30 |
| * | B | US-5,413,958 A | 05-1995 | Imahashi et al. | 438/487 |
| * | C | US-5,994,164 A | 11-1999 | Fonash et al. | 438/97 |
| * | D | US-RE36,371 E | 11-1999 | Imahashi et al. | 427/8 |
| * | E | US-6,218,198 B1 | 04-2001 | Imao et al. | 438/7 |
| * | F | US-6,281,470 B1 | 08-2001 | Adachi, Masahiro | 219/121.62 |
| * | G | US-7,405,141 B2 | 07-2008 | Jyumonji et al. | 438/487 |
| * | H | US-7,473,657 B2 | 01-2009 | Okumura, Hiroshi | 438/795 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP 2000114174 A | 04-2000 | Japan | ABE, HIROYUKI | H01L 21/20 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.